

Notice of References Cited	Application/Control No. 10/502,423		Applicant(s)/Patent Under Reexamination BASE ET AL.	
	Examiner Eueng-nan Yeh		Art Unit 2624	Page 1 of 1

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*	C	US-6,078,618	06-2000	Yokoyama et al.	375/240
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	U	Rui Zhang et al., IEEE, ACSSA, Vol. 1, 24-27 Oct 1999, 332-336
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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